



Report on “Industrial Visit to SAMEER MUMBAI CAMPUS”

Date: 28 February 2020

Time: 1:00 am – 5:00 pm

Venue: IIT Campus, Powai.

Target Audience: TE – EXTC Students

Participants: 26 TE-EXTC Students & 2 Faculty Members

Description:

- The Department of Electronics & Telecommunication Department of Don Bosco Institute organized an Industrial Visit to “SAMEER MUMBAI” on 28th Feb, 2020 for the third-Year students of Batch 2019-20. The visit began with an introduction by Mrs. Poornima Shrivastava who gave the students a brief overview of the organization as well as the different exhibits that were on display.
- After the introduction the students were guided towards an exhibition by the radar department of SAMEER. Systems like object detection using radar technology were demonstrated to give the students a basic idea of how a radar works.

Other exhibits included:

- Different types of antennas along with their pros and cons
 - Miniaturized versions of antenna that included sensors like altitude meters that could be used in aircrafts
 - Application specific radiation testing kits
 - Antenna manufacturing process
 - Tumor detection system
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- After interacting with the different stalls, the students moved to the MRI department wherein the students were shown a small video on the working of an MRI machine which was followed by a brief presentation which highlighted the need for development of an MRI machine in India. The presentation mainly focused on how cost reduction for an MRI machine which would eventually bring down the cost of MRI scanning will go down considerably for the average consumer thus allowing a wider section of people to have convenient access to the otherwise highly priced MRI scans. The students were then guided the MRI room which where the different components of the machine were explained.

- The students then proceeded towards the next exhibit which was the linear accelerator, developed indigenously at SAMEER which is used for treatment of cancer. The different components of the system like the accelerating tube and dosage control system were explained outside the facility followed by a video presentation shown on site, before the actual machine was shown to the visitors.
- After the session the students were free to observe the exhibits from the exhibition-cum-competition named “TECHNOLOGY CHALLENGE” which is an annual competition conducted by the organization on national science day.

Event photographs:



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Report Approved by - Ms. Gejo George- IEEE-DBIT SB Counselor